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Title: Advances in Copper Electrodeposition in Chloride Excess. A Theoretical and Experimental Approach

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Keywords: copper electrodeposition; Chloride effect; surface concentration; first stages; DES.

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Abstract: This is an in depth study in the knowledge of the nucleation and growth mechanism that governs copper electrodeposition in excess chloride media. In these conditions copper electro-reduction takes place via two well-separated steps, since the Cu(I) intermediate is stabilized through chloride complexation. The process was studied in two media, a deep eutectic solvent (DES) based on a mixture of urea and choline chloride, and in excess chloride aqueous solution, in order to also analyse solvent influence on the early stages of the deposition process. In both media, copper electrodeposition follows a nucleation and a diffusion controlled three-dimensional growth mechanism. In line with a previous work a double potentiostatic step signal was employed to record j-t transients associated to both nucleation and growth stages, and from them, the whole mechanistic analysis of the copper electrodeposition of Cu(II), free Cu(I) and complexed Cu(I) for any time and potential required and the application of Sharifker-Hills model, jm2tm products and rising part analysis including the calculated parameters, which are strengthened as valuable tools for complete copper electrodeposition analysis in these media.

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Barcelona, January 11, 2015

Dear Prof. Birbilis,

Please find enclosed the revised version of the manuscript entitled "Advances in Copper Electrodeposition in a Chloride Excess. A Theoretical and Experimental Approach" by P. Sebastián, E. Torralba, E. Vallés, A. Molina and E. Gómez_{\overline{x}} referenced as **NB14-440**.

After a careful reading of the reviewer's comments we agree with reviewer 1 in the partial reduction of the experimental content of the manuscript. In this line:

- a) Experimental section has been removed and merely specifies the different working temperature in DES, justifying the selection.
- b) The 4.1. General behaviour section has been reduced and concisely new DES related results are included. Figures 2 and 3 in the old version have been removed as well and only the corresponding results are included.
- c) An effort to reduce the text related to previously published results has been made along the text.
- d) Figures 9 and 12 in the old version have also been removed and the reader is referred to the previous paper (ref[26]) for more information about experimental procedures.

All changes are highlighted in yellow in the new version.

On the other hand, we would like to state that the experimental content of this manuscript was performed according to the conditions advised by the theoretical model. For this reason the results included do not coincide with those previously published. We consider that the rest of experimental figures are necessary to follow the argument of the manuscript.

Please find attached the answers concerning to the questions raised by referees 1 and 2 in the document "Response to the reviewers"

We hope that, this new version is now suitable to be published in Electrochimica Acta. Thank you in advance for your interest.

Yours sincerely,

The authors

Reviewer #1

First of all we would like to thank the reviewer for his/her constructive comments. In the following we answer to his/her questions and suggestions explaining the modifications we have made in this revised version following them.

Reviewer #1: The manuscript by P. Sebastian et all present in depth study of the nucleation and growth mechanism of copper electrodeposition with stabilization of intermediate through chloride complexation. Authors expand on their previous finding of "Copper electrodeposition in a deep eutectic solvent. First stages analysis considering Cu(I) stabilization in chloride media" which was published recently in Electrochim. Acta, 123 (2014) 285 earlier this year. Well written, the manuscript adds new details on intermediates involves in the Cu reduction, but experimentally, is trails path of the previous publication, along with similar experimental approach. As a matter of fact, same concentration of Cu (0.05 M CuCl2 in DES solvent) were used in both published and current experimental.

In this manuscript, the results derived for the Cu(II) electrodeposition in DES solvent correspond to a working temperature of 40°C, lower than that previously used in reference 26 of 70°. This lower temperature was selected in order to prevent the possible decomposition of the solvent at long working times. For this reason experimental results related to DES solvent were included in the text.

Some parts of the manuscript (especially experimental) were copy-pasted from the previous publication, the authors also carried over misprints. For instance, p.4 "Higroscopicity" instead of hygroscopicity into the current manuscript. Same misprint can be found on page 286 of published manuscript.

The experimental procedure was included in order to avoid the reader searching for the other paper. We apology for the misprint.

In this new version, the content of Experimental section has been removed, and merely specifies the working temperature in DES, justifying its selection.

I feel it would me more appropriate to focus only on theoretical parts of the modeling, referencing previous experimental results.

According to the reviewer suggestions, in this new version the 4.1. General behaviour section has been reduced and concisely DES related results are included. Figures 2, 3 in the old version have been removed as well. An effort to reduce the drafting of some paragraphs related to previous work has been made along the text.

With respect to the nucleation and growth section we would like to clarify that its experimental content is related to different residence times at the potential E1, according to the conditions needed to test the theoretical model, and so it corresponds to different experimental results that those previously obtained and published in Electrochim. Acta, 123 (2014) 285. Nevertheless, following the referee's suggestions Figures 9 and 12 of the old version related to the rising part analysis of the j-t transients have been removed and only their results are briefly presented. The reader is referred to the previous manuscript for more information about the experimental procedures.

Reviewer #2:

We would like to thank the reviewer 2 for his/her in-depth reading of the manuscript. In the following we answer to his/her questions in the same order that he/she stated them.

Reviewer #2: This paper presents an analysis of pulsed electrodeposition of copper in two concentrated chloride solutions - an aqueous NaCl solution and a deep eutectic choline chloride solvent (DES). High Cl- concentration stabilizes the Cu(I) intermediate, so the Cu+2/Cu+ and Cu+/Cu reactions occur at significantly different potentials. In the double pulse experiments, Cu+ species are produced at the first potential E1 and Cu deposited at the second potential E2. The Cu+2/Cu+ reaction at E1 is modeled by a classic EC mechanism with diffusion controlled electrode reaction and Cl- complexation the chemical step. The deposition process at E2 is treated by the Sharifker-Hills diffusion-controlled electrochemical nucleation and growth model. The analysis appears to be successful, so that apparently these high Cl- concentration experiments remove the ambiguity typically produced when the potential ranges of the two processes overlap significantly. The model and results are presented clearly and the paper is generally well written.

Copper electrodeposition is important in fabrication of interconnects for semiconductor devices, and chloride at low concentrations is an important additive in the damascene baths for this process. In particular, chloride appears to accelerate deposition by an unknown mechanism (even without other additives). Also, there is a lot of recent work on electrodeposition from nonaqueous solutions. Therefore, there is considerable interest in this topic and so the paper is appropriate for Electrochimica Acta. I recommend publication with minor revisions.

This paper seems to constitute progress towards quantitative treatment of chloride effects on electrodeposition. From the results, both the Cu+2/Cu+ reactions and the growth of nuclei are under diffusion control, with only the chloride complexation reaction controlled by kinetics. In fact, it is shown that after sufficient time at E1, the complexation reaction is also at equilibrium. Would the model apply at the low chloride concentrations of greater technological interest? Does the model provide insight into possible acceleration mechanisms at low chloride concentration?

In the development of our theoretical model we assume that the bulk concentration of chloride ion in solution is large enough compared with that of Cu(I) in order to a pseudofirst-order kinetics is satisfied. If this condition is not fulfilled our model could not be applied and the mass transport should be solved numerically. So, high chloride concentrations are required.

The authors mention that the voltammetric peak separation in DES is much larger than expected for diffusion-controlled reactions, and suggest that the ohmic resistance of the solution may be significant. It seems that proper inclusion of ohmic effects could dramatically change the model. Migration terms in the species balances and the electroneutrality condition would be included to fully account for migration effects. Why is this model still valid if migration is important?

One of the main disadvantages of sweep voltammetric techniques like CV is the distortion caused by the combination of the double layer charging process with the ohmic drop, related with the uncompensated resistance of the solution. This distortion is much less severe in pulse techniques, due to the discrete nature of the recorded current [V. Mirceski, S.Komorsky-Lovric, M. Lovric in Square-Wave Voltammetry, Theory and Application, Springer, Heidelberg 2007]. Our theoretical model is derived for the application of a single potential pulse (Normal pulse voltammetry) so it is expected that under the experimental conditions selected the IR effect is not significant on the NPV response. Moreover, the ionic concentration of inert electrolyte in both aqueous and DES medium is so high in comparison with the copper concentration that it can be expected

that the migration effects will not have significant influence [J. Phys. Chem. 2009, 113, 11157-11171]

Advances in Copper Electrodeposition in Chloride Excess. A Theoretical and Experimental Approach

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Abstract

This is an in depth study in the knowledge of the nucleation and growth mechanism that governs copper electrodeposition in excess chloride media. In these conditions copper electro-reduction takes place via two well-separated steps, since the Cu(I) intermediate is stabilized through chloride complexation. The process was studied in two media, a deep eutectic solvent (DES) based on a mixture of urea and choline chloride, and in excess chloride aqueous solution, in order to also analyse solvent influence on the early stages of the deposition process. In both media, copper electrodeposition follows a nucleation and a diffusion controlled three-dimensional growth mechanism. In line with a previous work a double potentiostatic step signal was employed to record j-t transients associated to both nucleation and growth stages, and from them, the whole mechanistic analysis of the copper electrodeposition was performed. This analysis involved the calculation of the surface concentrations of Cu(II), free Cu(I) and complexed Cu(I) for any time and potential required and the application of Sharifker-Hills model, $j_m^2 t_m$ products and rising part analysis including the calculated parameters, which are strengthened as valuable tools for complete copper electrodeposition analysis in these media.

Keywords: copper electrodeposition, first stages, surface concentration, chloride effect, DES

Copper electrodeposition has been for a long time an important topic due to the interest that copper coatings have in a wide range of applications. This has been heightened yet more by the massive use of copper in the electronics industry [1-4].

As it is well known, the presence of free or complexed cations in solution has an important role on the overall deposition process, as they strongly affect both nucleation and growth. In the copper's case, for instance, some commercial and laboratory copper deposition baths incorporate species which can act as complexing agents, some of them (such as ammoniac, chloride, bromide, cyanide, thiocyanide, etc.) acting as well as complexing agents for the Cu(I) intermediate [5-7].

Due to its fundamental and theoretical importance there is no lack of reports related to the Cu deposition mechanism [8-14]. However, to the best of our knowledge, there is no literature with takes into consideration a possible intermediate stabilization when performing the mechanistic analysis via chronoamperometric method. The mechanistic analysis of the first deposition stages using chronoamperometric data has usually been performed by recording the response after the application of a typical single potentiostatic step. This procedure, however, does not lead to reliable results when stabilization of the intermediate occurs, so that comments related to divergent or unexpected results have been included in some of the reports [4,15-17].

Recently it has been proved that ionic liquids based on eutectic mixtures of choline chloride and hydrogen bond donors (known as deep eutectic solvents (DES)) can be used for copper electrodeposition [18-21]. In these media, chloride is present in excess (about 5M) and the intermediate Cu(I) is stabilized by complexation with it, such that the complete electroreduction process takes place via two well-separated one-electron

stages. This behaviour is similar to that previously observed in aqueous concentrated chloride solutions [22-25]. In a previous work the first stages of Cu(II) reduction were studied in two chemical systems having in common a chloride excess (DES and aqueous concentrated chloride solution) [26]. In both media, it was proposed to apply a double-step signal in the chronoamperometric study as an adequate procedure to obtain reproducible results on nucleation and growth processes. The overall profile of the j-t response obtained by using this double-step signal presents two clear zones related to Cu(II) to Cu(I) reduction and to the Cu electrodeposition from Cu(I). The purpose of this work is to extend the previous studies and to deepen the knowledge of the mechanism governing Cu(II) electro-reduction by carrying out the complete quantitative analysis of the two reduction processes mentioned above. This requires knowing the surface concentration of the ionic species of interest on the electrode at the instant in which the second potential step is applied, which enables the proper selection of the residence time value at the first applied potential and so the control of the conditions at which the electrodeposition starts. In this line, a quantitative study that allows evaluation of the surface concentrations of the species involved in the first stages of the deposition process (i.e. Cu(II), free Cu(I) and complexed Cu(I)) has been carried out in both media (aqueous solvent and DES), using analytical equations for the current/potential response and surface concentrations obtained assuming that these first stages follow an EC reaction scheme [27, 28]. The equations obtained enable us to estimate the formal potential of the Cu(II)/Cu(I) couple and the complexation reaction rate constant values between Cu(I) and chloride in the two media by nonlinear fitting between experimental data and theoretical equations. Once the process has been characterized, the surface concentration values of Cu(II), free Cu(I) and complexed Cu(I) at any experiment time are readily obtained. Afterwards, the non-dimensional

Scharifker and Hills (S-H) model [29, 30] has been used to analyze the nucleation and growth deposition processes, an approach that has already been applied recently to deposition processes in ionic liquids [26, 31-34]. As will be shown, the knowledge of surface concentration values allows the complete quantitative analysis to be accomplished.

2. Experimental

The preparation of solutions and the electrochemical experiments were performed in the same way that had been previously described in reference [26]. The selected temperature in DES solvent was 40°C, lower than in [26], in order to assure liquid stability at long working times.

3. Theory

It has been demonstrated that in a excess of chloride medium the intermediate Cu(I) coming from the Cu(II) reduction in the first stage of the reduction process stabilizes by complexation, and so the complete electrochemical process occurs by means two well separated one-electron stages (Cu(II)-Cu(I) and Cu(I)-Cu(0)) [26].

3.1. Theoretical model for the first stage of the cooper electrodeposition in excess of chloride medium: Cu(II)/Cu(I) reduction facilitated by chloride complexation.

In this section we focus in the theoretical model of the mass transport problem corresponding to the first stage of the copper electrodeposition under chloride excess

(Cu(II)/Cu(I) reduction facilitated by chloride complexation) by assuming that it takes place via an EC process:

$$Cu(II) + e^{-} \xleftarrow{cu(I)} Cu(I)$$
$$Cu(I) + mCl^{-} \xleftarrow{k_{1}} Cu(Cl)_{m}$$

where k_1 and k_2 indicate the forward and backward kinetic constants of the chemical reaction taken to be of pseudo-first order and m = 2 or 3 (i.e. $Cu(Cl)_m = Cu(Cl)_2^-$ or $Cu(Cl)^{2^-}$)

$$Cu(Cl)_3$$
).

When a constant potential, E_1 , is applied to this system at a planar electrode, mass transport can be described by the following diffusive-kinetic equation system and boundary value problem:

$$\hat{\delta}_{Cu(II)} = 0$$

$$\hat{\delta}_{Cu(I)} = -k_1 c_{Cu(I)}(x,t) + k_2 c_{Cu(CI)_m}(x,t)$$

$$\hat{\delta}_{Cu(CI)_m} = k_1 c_{Cu(I)}(x,t) - k_2 c_{Cu(CI)_m}(x,t)$$
(1)

being

$$\hat{\delta}_i = \frac{\partial}{\partial t} - D_i \frac{\partial^2}{\partial x^2} \tag{2}$$

$$\begin{array}{l} t = 0, \quad x \le 0 \\ t \ge 0, \quad x \to \infty \end{array} \} \quad c_{Cu(II)}(x,t) = c^*, \quad c_{Cu(I)}(x,t) = 0, \quad c_{Cu(CI)_m}(x,t) = 0$$
(3)

x = 0, t > 0

$$D_{Cu(II)}\left(\frac{\partial c_{Cu(II)}(x,t)}{\partial x}\right)_{x=0} = -D_{Cu(I)}\left(\frac{\partial c_{Cu(I)}(x,t)}{\partial x}\right)_{x=0}$$
(4)

$$D_{Cu(Cl)_m}\left(\frac{\partial c_{Cu(Cl)_m}(x,t)}{\partial x}\right)_{x=0} = 0$$
(5)

$$c_{Cu(II)}(0,t) = c_{Cu(I)}(0,t)e^{\eta}$$
(6)

with η given by

$$\eta = \frac{F}{RT} \left(E_1 - E_{Cu(II)/Cu(I)}^{0'} \right)$$
(7)

In these equations, $c_i(x,t)$ and D_i are, respectively, the concentration of the species *i* and its diffusion coefficient, c^* is the bulk concentration of species Cu(II) and other symbols have their usual meaning.

The solution for this problem has been derived rigorously for spherical and planar electrodes by assuming equal diffusion coefficients for all the species involved in the EC process [36] (i.e. $D_{Cu(II)} = D_{Cu(II)} = D_{Cu(CI)_m}$ in this particular case). If different diffusion coefficients are considered for species Cu(II) and Cu(I) and supposing that the function perturbation of the chemical equilibrium ($\phi(x,t) = c_{Cu(I)}(x,t) - Kc_{Cu(CI)_m}(x,t)$) does not depend on time (i.e. assuming kinetic steady state conditions (kss)) [28, 37] the following expression for the j/E/t response is derived

$$\frac{j_{EC}}{j_d} = \frac{(1+K)}{1+K+K\gamma e^{\eta}} F\left(\chi^{EC}\right)$$
(8)

where χ^{EC} , *K* and γ are given by

$$\chi^{EC} = \frac{2\sqrt{\chi}}{\gamma e^{\eta}} \left(1 + K + K\gamma e^{\eta} \right) \tag{9}$$

$$K = k_2 / k_1 \tag{10}$$

and

$$\gamma = \sqrt{\frac{D_{Cu(II)}}{D_{Cu(I)}}} \tag{11}$$

with χ being the dimensionless rate constant of the complexation reaction

$$\chi = \left(k_1 + k_2\right)t \tag{12}$$

 j_d the diffusion limited current density

$$j_d = -FA \sqrt{\frac{D_{Cu(II)}}{\pi t} c^*}$$
(13)

and F(x) being given by

$$F(x) = \sqrt{\pi} \frac{x}{2} e^{(x/2)^2} erfc\left(\frac{x}{2}\right)$$
(14)

Equation (8) is applicable for any *K* value provided $(k_1 + k_2)t \ge 5$ [38].

Note that K given by Eq. (10) represents the inverse of the equilibrium constant taken of pseudo-first order with respect to Cu(II). The expression for the real equilibrium constant of the complexation reaction is

$$K^{real} = \frac{1}{K(c_{Cl^{-}})^{m}} = \frac{c_{Cu(Cl)_{m}}}{(c_{Cu(I)})(c_{Cl^{-}})^{m}}$$
(15)

The expression for the surface concentrations for all the species involved in the first stage of the electrodeposition process are obtained by following a similar procedure to that used in Ref [28] and have the following form

$$\frac{c_{Cu(II)}(0,t)}{c^{*}} = 1 + \frac{1+K}{1+K+K\gamma e^{\eta}} \left\{ \frac{2}{\sqrt{\pi}} \frac{F(\chi^{EC})}{\chi^{EC}} - I \right\}$$

$$c_{Cu(I)}(0,t) = c_{Cu(II)}(0,t) / e^{\eta}$$

$$\frac{c_{Cu(CI)_{m}}(0,t)}{c^{*}} = -\frac{1}{e^{\eta}} \left[1 + \frac{(1+K)(1+\gamma e^{\eta})}{1+K+K\gamma e^{\eta}} \left\{ \frac{2}{\sqrt{\pi}} \frac{F(\chi^{EC})}{\chi^{EC}} - I \right\} \right]$$
(16)

When $\chi^{EC} \ge 21.5$, the diffusive-kinetic steady state (*dkss*) approximation applies [22, 33]. Under these conditions, $F(\chi^{EC}) = \sqrt{\pi} \chi^{EC} / (2 + \sqrt{\pi} \chi^{EC})$ and Eq. (8) for the j/E/t response simplifies to

$$\frac{j_{EC}}{j_d} = \frac{1+K}{1+K+\gamma e^{\eta}(K+1/\sqrt{\pi\chi})}$$
(17)

This response is quite interesting since it can be linearized in an identical way to that corresponding to a simple E process, so we have

$$E = E_{1/2} + \frac{RT}{F} \ln\left(\frac{j_d - j_{EC}}{j_{EC}}\right)$$
(18)

with $E_{1/2}$ being the half-wave potential

$$E_{1/2} = E_{Cu(II)/Cu(I)}^{0'} + \frac{RT}{F} \ln\left(\frac{1}{\gamma}\right) + \frac{RT}{F} \ln\left(\frac{(1+K)\sqrt{\pi\chi}}{1+K\sqrt{\pi\chi}}\right)$$
(19)

Expressions (17) - (19) could be used for a general good description of the system instead of those deduced under kss conditions [28, 37] and are very helpful to estimate the values of $E_{1/2}$, K and/or χ avoiding numerical fitting, as is shown in Figure 6.

3.2. Treatment for the Nucleation and Growth:

The mechanistic analysis of the Cu(I)-Cu(0) electrodeposition was performed from the chronoamperometric results using the well-known Scharifker and Hills (S-H) model, developed for nucleation and three-dimensional growth diffusion controlled, whose basis are well-established and which can be consulted elsewhere [29, 30]. The two non-dimensional equations given by Eqs. (20) and (21) correspond to the limiting cases of progressive and instantaneous nucleation, respectively. The former is associated with nuclei sequential appearance whereas the latter identifies with simultaneous nuclei formation:

$$\left(\frac{j}{j_m}\right)^2 = 1.2254 \left(\frac{t}{t_m}\right)^{-1} \left[1 - \exp\left(-2.3367 \left(\frac{t}{t_m}\right)^2\right)\right]^2$$
(20)

$$\left(\frac{j}{j_m}\right)^2 = 1.9542 \left(\frac{t}{t_m}\right)^{-1} \left[1 - \exp\left(-1.2564\frac{t}{t_m}\right)\right]^2 \tag{21}$$

where j and t represent, respectively, the current density and the time during the nucleation and growth stages, and j_m and t_m are the values of these magnitudes at which the potentiostatic maximum is attained.

By assuming that the charge-transfer rate for copper deposition is sufficiently high for a continued growth of nuclei through mass transfer control to be established and that there is no overlapping of the nuclei randomly distributed on the surface, the rising part of the j-t transients can also be used as an adequate tool for mechanistic analysis. The corresponding equations derived for progressive and instantaneous nucleation, respectively, are the followings

$$j = \frac{2}{3} z F \pi (2Dc)^{\frac{3}{2}} M^{\frac{1}{2}} \rho^{-\frac{1}{2}} N_o A t^{\frac{3}{2}}$$
(22)

$$j = zF\pi (2Dc)^{\frac{3}{2}} M^{\frac{1}{2}} \rho^{-\frac{1}{2}} N_o t^{\frac{1}{2}}$$
(23)

where *D*, is the diffusion coefficient of the depositing species, *c*, *M* and *zF* are its concentration, molecular weight, and molar charge, respectively, ρ is the density of the solution, *N*_o the maximum number of nuclei obtainable under the prevailing conditions and *A* the steady state nucleation rate constant per site [29].

As an extra diagnostic criterion to study the nucleation mechanism governing the process, the $j_m t_m^2$ products for the limiting cases of progressive and instantaneous nucleation (Eqs. (24) and (25), respectively) can be used to determine whether the nucleation process is progressing or has been arrested, by taking advantage of the surface concentration values previously obtained. The $j_m t_m^2$ products do not contain quantities related to kinetic parameters, fact that makes them valuable [29].

$$j_m^2 t_m = 0.260 (Fcz)^2 D \tag{24}$$

$$j_m^2 t_m = 0.163 (Fcz)^2 D \tag{25}$$

4. Results and discussion

4.1. General behaviour

The voltammetric curves recorded in both media (Fig. 1) showed similar profile, the peaks corresponding to the Cu(II)-Cu(I) reduction were followed by a second group of features at more negative potentials related to Cu(I) electrodeposition [26].

<Figure 1>

 In aqueous chloride medium the peaks related to Cu(I) electrodeposition were sharper and less negative than those recorded in the DES. The inset in Figure 1 shows a good coincidence between the voltammetric curves recorded from Cu(II) and Cu(I) solutions in the potential range where copper electrodeposition takes place.

The diffusion coefficients of Cu(II) and Cu(I) in the DES solution at 40°C were respectively determined from voltammetric experiments and potentiostatic electrodeposition transients as described in reference [26]. Cyclic voltammograms were recorded at different scan rates. The differences $|E_{p,c}-E_{p,a}|$ between the cathodic and anodic peak potentials (Table 1) approached 85 mV at the lowest scan rates and increased as the scan rate did, behaviour that can be ascribed to the resistance of organic media [21]. The Cu(II) diffusion coefficient calculated according to eq (26) [27]

$$jp, c = 0.4463 * \left(\frac{F^3}{RT}\right)^{1/2} * n^{3/2} * D^{\frac{1}{2}}[Cu(II)]v^{\frac{1}{2}}$$
(26)

was $2.24 \cdot 10^{-8}$ cm²s⁻¹, consistent with previously reported values at other temperatures [21, 26].

<Table 1>

The Cu(I) diffusion coefficient was determined in a 0.05 M CuCl solution. The ends of the descending part of the recorded transients overlapped as befits a diffusion controlled process. Adjustment according to the well-known Cotrell equation leds to an average value of 2.08 · 10⁻⁷ cm²s⁻¹.

4.2. Surface concentration

The complete analysis of copper reduction was made by an accurate potentiostatic study using the double step signal proposed previously [26]. At first the potential was jumped from a potential (E_0) where no process occurred to a potential (E_1) at which only the reduction of Cu(II) to Cu(I) took place (Fig. 2A). After a residence time (t_1) in the potential E_1 , the potential was switched to a potential E_2 at which electrodeposition occurred. The recorded current showed two clear features, at first the current decayed monotonically to a quasi-stationary value (Fig. 2B) and, after applying the E_2 potential, the transient showed the typical profile of a nucleation and 3D growth process (see Figures 5, 6A and 8A).

<Figure 2>

A quantitative study was carried out to obtain information about the surface concentrations on the electrode along the residence time (t_1) . Figure 3 displays the dependence on time of the surface concentrations of the species participating in the first stage of the copper reduction (i.e. Cu(II) to Cu(I) facilitated by chloride complexation) in the two media selected (aqueous solvent and DES, Figs. 3A and 3B respectively) obtained by applying Eq. (16). The E₁ values selected, 0V in aqueous solution and - 0.1V in DES, were chosen according to the previous voltammetric results.

<Figure 3>

To build these plots it was taken into account that Cu(I) can bind either two or three chloride ions, giving rise to two different chloride complexes $Cu(Cl)_m$ (where m = 2 or 3, solid and dotted lines, respectively, in the Figure 3). The stability constant of the two different complexes was estimated in water using the information given in Ref [39] as

 $K_{water}^{real} = 10^{5.5}$ for the complex with m = 2 and $10^{5.7}$ for the complex with m = 3. For the theoretical calculations, the equilibrium between the complexed and uncomplexed Cu(I) in DES was considered to be highly displaced towards the complexed species ($K_{DES}^{real} \approx K_{water}^{real} >>1$).

The values of $k_1 + k_2$ ($\approx k_1$ for these complexation reactions highly displaced to the products) required for χ^{EC} to be known (Eq. (9)) and to plot the surface concentrations were obtained by non-linear fitting between the experimental Normal Pulse Voltammetric (NPV) signals and the theoretical ones (Eq. (8)) as depicted in Figure 4. Chronoamperometric experiments at different potentials at which only the facilitated Cu(II) to Cu(I) reduction took place were used to build the experimental NPV responses.

<Figure 4>

Tentative initial values required for k_i were obtained by introducing experimentally determined $E_{1/2}$ values in Eq.(19). These $E_{1/2}$ values were estimated by the linearized E_1 versus $(j_d - j_{EC})/j_{EC}$ plots (Eq. (18)) as shown in the inset figures. The tentative initial value used for $E_{Cu(II)/Cu(I)}^{0'}$ was 159 mV, obtained from the literature [27].

The optimum values of $E_{Cu(II)/Cu(I)}^{0'} E_{Cu^{+2}/Cu^{+1}}^{0'}$ and k_1 that yielded the best fitting were 162 mV and 29×10³ s⁻¹ for the data obtained in the aqueous solvent, and 168 mV and 12× 10³ s⁻¹ for that obtained in DES. From these, the values for the real forward kinetic constant of the complexation reaction $k_1^{real} \left(=k_1 / (c_{CI})^m\right)$ were obtained in the two media for the two possible complexes considered (i.e. those with m = 2 or 3) as $k_1^{real} \approx$

 $3.2 \times 10^3 \text{ M}^{-2} \text{ s}^{-1}$ and $1.1 \times 10^3 \text{ M}^{-3} \text{ s}^{-1}$ for the complexes with m = 2 and 3, respectively, in the aqueous solvent, and $k_1^{real} \approx 4.8 \times 10^2 \text{ M}^{-2} \text{ s}^{-1}$ and $10^2 \text{ M}^{-3} \text{ s}^{-1}$ for the complexes in DES.

Several conclusions can be drawn from the analysis of the plots given in Figure 3. First, it can be seen that the surface concentration of Cu(II) is almost always zero at any time of the experiment in both water and DES. These applied potentials correspond to conditions of diffusion controlled current for the Cu(II)/Cu(I) reduction, beneficial conditions to the generation of Cu(I). Besides, it is observed that as time increases the concentration at the electrode surface of complexed Cu(I) increases, at the expense of a decrease in the surface concentration of free Cu(I). The observed variation is slight for both media, such that $c_{Cu(Cl)_m}(0,t)$ approximates quickly to the limiting value of γc^* (Eq. (27)), which corresponds to 4.946 10⁻³ and 16.393 10⁻³ M in the aqueous media and in DES (Figs. 3A and 3B), respectively.

Under diffusion controlled conditions $(E_1 \ll E_{Cu(II)/Cu(I)}^{0'})$ and for complexation reactions highly displaced toward the products $(K^{real} \gg 1 \text{ or } K \ (= k_2/k_1) \ll 1)$, the surface concentrations involved in the EC mechanism simplify to

$$\frac{c_{Cu(II)}(0,t)}{c^{*}} = 0$$

$$\frac{c_{Cu(I)}(0,t)}{c^{*}} = \frac{\gamma}{\sqrt{\pi\chi}}$$

$$\frac{c_{Cu(CI)_{m}}(0,t)}{c^{*}} = (1 - 1/\sqrt{\pi\chi})\gamma$$
(27)

with c^* being the initial concentration of Cu(II) in solution and γ and χ given by Eqs. (11) and (12), respectively. From Eq. (27) it can be seen that when time increases and $\chi(=(k_1+k_2)t) \gg 1$, the surface concentrations of free and complexed Cu(I) tend to zero and to γc^* , respectively. Equation (27) constitutes a simple set of expressions that are adequate to obtain the evolution of the surface concentration with time in our system.

Note that, under the conditions selected there is no difference between the curves corresponding to the complex with m = 2 and m = 3, which coincides with the behaviour predicted by Eq. (27).

4.3. Nucleation and growth

In order to address the study of the electrodeposition process in both media, different residence times within the time range in which the surface concentrations showed a quasi-stationary value were selected ($t_1 = 15$, 30 and 45s). After the E₂ application, new j-t transient appeared showing the typical nucleation and 3D growth controlled by diffusion profile.

For the three residence times selected the comparison of the transients recorded at a given E_2 did not reveal significant differences in the rate of the deposition process (Fig. 5A and 5B). Indeed, quasi coincidence was observed in the current profiles, the current maxima (j_m) and the time elapsed (t_m) between the E_2 application, and also on the achievement of the current maximum. These results are in agreement with those provided by the theory, with the Cu(I) concentration reaching a constant value from a certain t_1 .

<Figure 5>

4.3.1. Copper electrodeposition in aqueous chloride excess medium

In aqueous chloride excess medium several j-t transients were recorded by means of the double step signal for all the t_1 selected, at different values of E_2 keeping E_1 at 0V. On increasing the overpotential applied the recorded current increased and the maximum was attained at a lower time. Note that a narrow potential range (c.a. 20 mV) was sufficient to observe relevant changes in the recorded j-t transients.

Figures 6A and 6B show, respectively, the j-t transients recorded at t_1 =15s and the corresponding adjustment to the non-dimensional S-H model. The adjustment of the j-t transients was made once the current related to Cu(II)-Cu(I) reduction was subtracted from the total current to avoid overestimation of the current related to copper electrodeposition. The S-H adjustment showed that the nucleation mechanism was intermediate and close to instantaneous even at the lowest overpotentials applied.

<Figure 6>

The analysis of the rising part of the experimental transients (Eqs. (22) and (23)) revealed that, for the lowest overpotentials applied, the slopes were close to 0.7, and on increasing overpotential, the slope tended to 0.5, as corresponds to instantaneous nucleation (see also reference [26]). These results are in well agreement with those provided by S-H adjustment, so, in aqueous chloride excess the nucleation was close to the instantaneous one.

In order to analyse the possible influence of the residence time on the nucleation mechanism, the adjustment of S-H model for several j-t curves recorded at a fixed E_2 and different t_1 values were compared (Fig. 7A). Non relevant differences were found in the time range previous to the maximum. However, the adjusted data from t>t_m showed slight differences. The curve corresponding to t_1 =45s appeared farther to the

instantaneous limiting case than those recorded after 15s or 30s. This can be explained by taking into consideration that extending the residence time in the Cu(II)-Cu(I) electro-reduction zone could favour, in the aqueous medium, the formation of a low amount of insoluble CuCl species, which could perturb the deposit growth. Thus, the data recorded after 15s were considered more reliable for the mechanistic analysis.

<Figure 7>

The knowledge of surface concentrations of Cu(I) (see Fig. 3) at the instant that E_2 was applied allowed the use of the products $j_m^2 t_m$ as an extra tool to analyze the nucleation mechanism. For t_1 =15s the surface concentration was $4.9 \cdot 10^{-3}$ M, which together with a value for the Cu(I) diffusion coefficient of $1.5 \cdot 10^{-5} \text{cm}^2 \text{s}^{-1}$ [26] yielded $j_m^2 t_m$ products of 8.87 10^{-7} and 5.56 10^{-7} A²cm⁻²s for progressive and instantaneous nucleation, respectively. The obtained $j_m^2 t_m$ products (Table 2) evolved on increasing the overpotential from $7 \cdot 10^{-7}$ to $6 \cdot 10^{-7}$ A²cm⁻²s, values close to those predicted for instantaneous mechanism. These results in good agreement with both those obtained from the overall S-H adjustment and those from rising part analysis, also indirectly support the results derived from the theoretical treatment of the potentiostatic curves recorded at E_1 , which predict the appropriate concentration value of complexed Cu(I) species on the surface of the electrode.

<Table 2>

4.3.2. Copper electrodeposition in the DES solvent

Proceeding in a similar way as in the aqueous medium, sets of j-t transients were recorded in DES at different residence times within the time zone at which the surface concentrations attained a stationary value. In the DES solvent a wide overpotential range was needed to observe significant changes in the recorded currents.

<Figure 8>

The comparison between experimental (Fig. 8A) and theoretical curves obtained from the S-H model (Fig. 8B), proved that in the DES solvent the nucleation mechanism was intermediate, near to progressive at the lowest applied overpotential, but without fully attainment of the instantaneous limit with significant E_2 increase. Therefore, from the non-dimensional analysis, the effect of the solvent nature on the mechanism seems clear. The growth of the nucleus formed was slowed by DES even for moderate temperatures (40°C), effect observed previously for the deposition of other metals [32].

Complementary analysis of the mechanism which governs the formation of the first nucleus was also made by logarithmic analysis of the rising part of the j-t curves at short deposition times in the same way depicted in reference [26]. The slopes calculated evolved from 1.0 to 0.6 on increasing the overpotential, i.e. the nucleation tended to instantaneous nucleation when considerably increasing the overpotential but this limit was not fully attained as observed with the S-H fittings.

It is worth noting that in DES both the j-t curves recorded a fixed E_2 after different residence times (t₁) and the corresponding non-dimensional adjustments did not show significant differences with respect to the t₁ value selected, as occurred in aqueous medium. The non-dependence between the residence time in E_1 and the electrodeposition process once the surface concentration of Cu(I) behaves in a stationary manner was confirmed by comparison of the S-H adjusted curves obtained at the different residence times selected (Fig. 7B). In DES medium good agreement between experimental and adjusted curves was found even at long deposition times. This behaviour could be related to both the higher chloride concentration in the DES and the specific nature of this ionic solvent that benefits the intermediate Cu(I) complexation, avoiding the possible non-soluble Cu(I) species formation.

Using the surface concentration at the beginning of the electrodeposition process (0.01694 M) and the calculated diffusion coefficient, the products $j_m^2 t_m$ predicted by equations (24) and (25) for the limiting cases were calculated and compared with those obtained from the extracted parameters from the experimental j-t curves. All the $j_m^2 t_m$ products obtained from the experimental data reproduced the magnitude order predicted by theory, although they were slightly higher than the value corresponding to progressive nucleation (not shown), which is always the highest value.

According to the literature, in DES solvent copper species are entirely complexed by chloride [40], but no information about the equilibrium constants values is provided, neither of the E^0 value of the couple Cu(II)/Cu(I) at DES. So, we used the *K* and E^0 values corresponding to aqueous medium as the initial guess values in the subsequent non-linear fitting of the experimental data. This first approximation could explain the slight discrepancy between the $j_m^2 t_m$ products from experimental values with those calculated theoretically.

The coherency between the results provided by the complete analysis with the S-H model and the analysis of the rising part of the transients confirms that an appropriate control of the initial conditions in the first stages of the electrodeposition and in the stationary concentration of Cu(I) on the surface was achieved, although in the DES medium this concentration value seems to be slightly underestimated.

5. Conclusions

In chloride excess medium the stabilization of the Cu(I) intermediate by chloride complexation slows down the second reduction stage and implies an extra overpotential to get electrodeposited copper. The double step potential method allows to study accurately the kinetics related to each step of the reduction.

From the j-t curves recorded along the first reduction step and by applying the appropriate equations which describe the kinetics of the Cu(II)-Cu(I) reduction, the surface concentration versus time functions are deduced for a fixed potential, and the values of the surface concentrations of Cu(II), free Cu(I) and complexed Cu(I) present in the electrode are estimated in any condition. As these surface concentrations achieve a stationary value, it is shown that residence times greater than this stationary value are suitable to initiate the electrodeposition process at controlled conditions. From this knowledge, the length of the first step is selected by setting the residence time at which electrodeposition begins. Under these conditions, the analysis of the mechanism related to the first stages of the copper electrodeposition from Cu(I) is performed successfully in an aqueous concentrated chloride solution and in a Deep Eutectic Solvent (DES) providing reliable results, in agreement with those expected. In DES at the selected temperature progressive nucleation to intermediate is observed in a wide potential range, whereas in aqueous medium instantaneous nucleation is easy to get, a behaviour which is always supported by the logarithmic analysis of the rising part of the j-t transients.

The S-H non-dimensional analysis at a fixed E_2 value shows slight dependence on the growth mechanism between the results obtained at different residence times in aqueous medium and none in DES, so the selection of a residence time value close to that

providing the stationary surface concentration theoretically predicted is enough for the appropriate mechanistic analysis.

The incorporation of the calculated surface concentrations in the jm²tm products provides excellent concordance in aqueous medium, conditions at which thermodynamic parameters are available, showing the performance of the theoretical treatment. A slight displacement between experimental and calculated jm²tm values is observed in the DES medium, in which underestimated concentration values seem to have been obtained probably due to the uncertainty in the estimation of the formal potential.

The results obtained sustain the use of the double step mode as a very good approximation to analyze accurately the Cu electrodeposition in both water and DES when considering the stabilization of the Cu(I) intermediate by complexation, avoiding the uncertainty associated with the application of a single step. Additional studies that not only rely on voltammetric data would be highly beneficial to know more of the physicochemical properties of this novel solvent and to understand how better it affects thermodynamic and kinetic parameters of the charge transfer and complexation reaction so as to refine model predictive abilities.

The strategy developed here for the analysis of the copper electrodeposition by using experimental data of the two electrochemical steps involved can be extended to any deposition process in which the overall reduction take place via two well separated stages.

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Figure captions

Fig. 1. Voltammetric curves at 50 mVs⁻¹ from: a) 0.05 M CuCl₂ in DES solvent and b) 0.01M CuCl₂ +3M NaCl aqueous solution. Inset: voltammetric curves in DES solution: solid line) 0.05 M CuCl₂ and dashed line) 0.05 M CuCl.

Fig. 2. A) Scheme of the applied double step signal. B) Potentiostatic current transients for the electro-reduction of Cu(II) to Cu(I) from 0.05M solutions of CuCl₂ in DES solvent at 40°C at different E_1 : a) 400, b) 380, c) 370, d) 350, e) 340, f) 330, g) 300, h) 250, i) 150, j) 0, k) -100 and m) -200mV.

Fig. 3. Time dependence of the surface concentrations of the species participating in the first stage of the copper electrodeposition in the two media selected (aqueous solvent and DES, Figs. 3A and 3B respectively) for the cases in which Cu(I) is complexed by two or by three chloride ions (m= 2 and m= 3, respectively, indicated by solid and dotted lines) obtained from Eq. (16). A) for aqueous solution: $(k_1 + k_2) = 29 \times 10^3 \text{ s}^{-1}$, $D_{Cu(II)} = 3.67 \times 10^{-6} \text{ cm}^2 \text{s}^{-1} D_{Cu(I)} = 1.5 \times 10^{-5} \text{ cm}^2 \text{s}^{-1}$, K (m=2) = 3.5×10^{-7} , K (m=3) = 7.4×10^{-8} , E₁ = 0 mV and c* = 10 mM. B) for DES: $(k_1 + k_2) = 12 \times 10^3 \text{ s}^{-1}$, $D_{Cu(II)} = 2.24 \times 10^{-8} \text{ cm}^2 \text{s}^{-1} D_{Cu(I)} = 2.08 \times 10^{-7} \text{ cm}^2 \text{s}^{-1}$, K (m=2) = 1.3×10^{-7} , K (m=3) = 1.6×10^{-8} , E₁ = -100 mV and c* = 50 mM.

Fig. 4. Experimental (symbols) and theoretical (lines) NPV responses at three different times of the experiment (t = 0.5, 1.5 and 2.5 s, indicated by crosses, circles and diamonds, respectively) for the Cu(II) to Cu(I) reduction facilitated by chloride complexation in: A) the aqueous solution and B) in DES. Theoretical curves were obtained by non-linear fitting of Eq. (8) to the experimental data by means of the Miner

function implemented in Mathcad. Tentative initial values for $(k_1 + k_2)$: 28700 and 12600 s⁻¹ for Fig. 4A and 4B, respectively. Tentative $E_{Cu(II)/Cu(I)}^{0'} = 159$ mV for both media. Other parameters were as stated in Figure 3. Inset: Linearized *E* vs $(j_d - j_{EC})/j_{EC}$ responses at the three times selected.

Fig. 5. Potentiostatic current transients at different residence times (t_1): a) 15 b) 30 and c) 45 s from: A) 0.05M solution of CuCl₂ in DES solvent, E_1 = -100 mV, E_2 = -1050 mV. B) 0.01M solution of CuCl₂ + 3M NaCl aqueous solution, E_1 = 0 mV, E_2 = -390 mV.

Fig. 6. A) Potentiostatic current transients for the deposition of copper from 0.01M $CuCl_2 + 3M$ NaCl aqueous solution, using the double step signal, $E_1 = 0$ mV, $t_1 = 15$ s and different E_2 : a) -360, b) -370, c) -390, d) -395, e) -400, f) -405 and h) -410 mV. B) Non-dimensional plots of $(j/j_m)^2$ vs t/t_m for some of the j-t transients of Fig. 6A.

Fig. 7. Non-dimensional plots of $(j/j_m)^2$ vs t/t_m for the copper electrodeposition j-t transients recorded at different residence times (t₁): a) 15 b) 30 and c) 45 s from: A) 0.01M CuCl₂ + 3M NaCl aqueous solution applying E₁= 0 mV and E₂= -405 mV. B) 0.05M CuCl₂ in DES solution applying E₁= -100 mV and E₂= -1050 mV.

Fig. 8. A) Potentiostatic current transients for the deposition of copper from a 0.05M CuCl₂ solution in DES, using the double step signal, E_1 = -100 mV, t_1 = 15 s and different E_2 : a) -950, b) -960, c) -975, d) -1000, e) -1050, f) -1100 and h) -1150 mV. B) Non-dimensional plots of $(j/j_m)^2$ vs t/t_m for some of j-t transients of Fig. 8A.

Characteristic values of E_{pa} , $E_{p,c}$, $|E_{pc}-E_{pa}|$, and $j_{p,c}$ for the anodic and cathodic peaks of the different CV voltammograms recorded from a 0.05 M solution of CuCl₂ in DES

v / mV s ⁻¹	E_{pa} / V	E_{pc} / V	$ E_{pc}-E_{pa} / V$	$j_{pc} 10^3 / A cm^{-2}$
5	0.393	0.307	0.086	0.1698
10	0.397	0.295	0.102	0.2200
20	0.401	0.286	0.115	0.3085
30	0.407	0.288	0.119	0.4192
50	0.417	0.283	0.134	0.5166
70	0.424	0.260	0.164	0.5906
100	0.429	0.256	0.173	0.6379
150	0.434	0.248	0.186	0.7871

solvent at different scan rates

E vs (Ag/AgCl)

Characteristics values for the potentiostatic current maximum and $j_m^2 t_m$ products for the j-t transients obtained from [Cu(II)]=0.01M + [NaCl]=3M in aqueous medium.

E/mV	t _m /s	$j_{\rm m} 10^3 / {\rm A \ cm^{-2}}$	$j_{m}^{2} t_{m} 10^{7} / A^{2} cm^{-4} s$
-360	2.55	-5.24	7.00
-370	1.47	-6.50	6.21
-390	0.76	-8.95	6.09
-395	0.61	-10.2	6.35
-400	0.39	-12.8	6.38

E vs (Ag/AgCl)

Characteristic values of E_{pa} , $E_{p,c}$, $|E_{pc}-E_{pa}|$, and $j_{p,c}$ for the anodic and cathodic peaks of the different cyclic voltammograms recorded from a 0.05 M solution of CuCl₂ in DES solvent at different scan rates

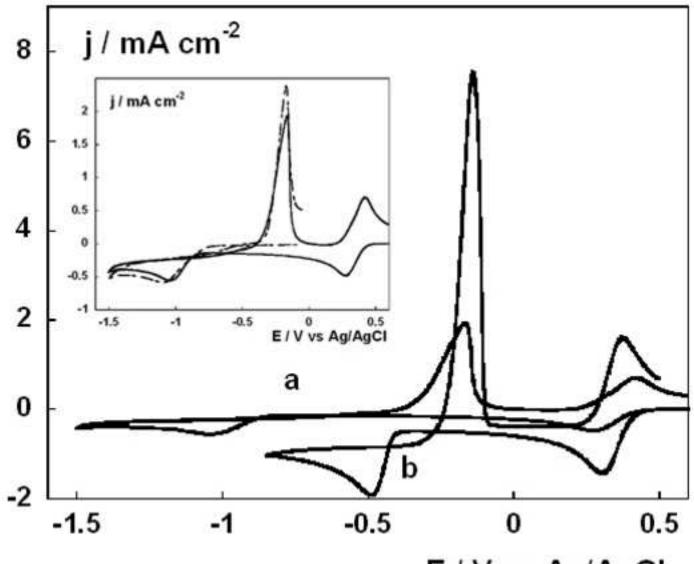
v / mV s ⁻¹	E _{pa} / V	E _{pc} / V	$ E_{pc}-E_{pa} / V$	$j_{pc} 10^3 / A cm^{-2}$
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E/mV	t _m /s	$j_{\rm m} 10^3 / {\rm A \ cm^{-2}}$	$j_m^2 t_m 10^7 / A^2 cm^{-4} s$
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-370	1.47	-6.50	6.21
-390	0.76	-8.95	6.09
-395	0.61	-10.2	6.35
-400	0.39	-12.8	6.38

E vs (Ag/AgCl)



E / V vs Ag/AgCI

Figure 1

Figure 2 Click here to download high resolution image

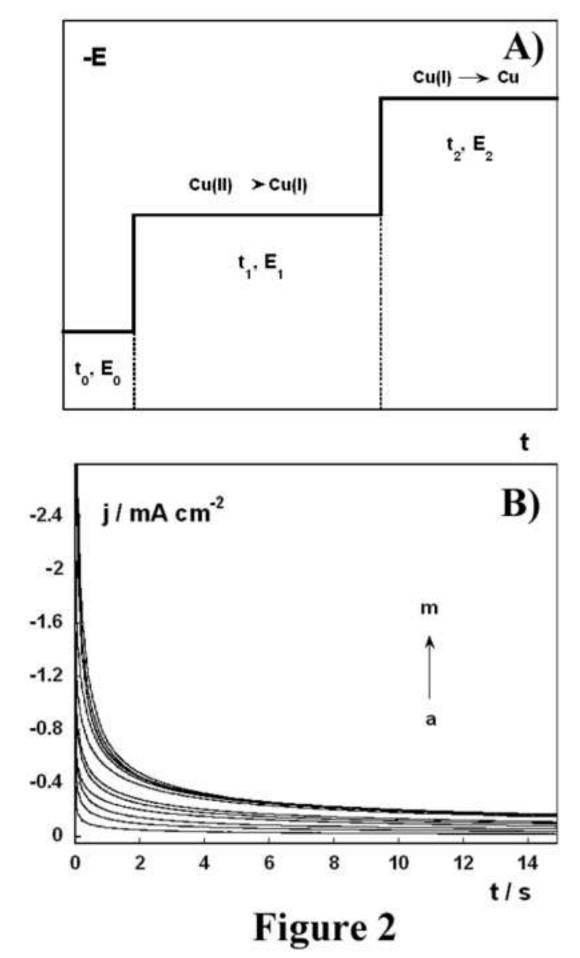


Figure 3 Click here to download high resolution image

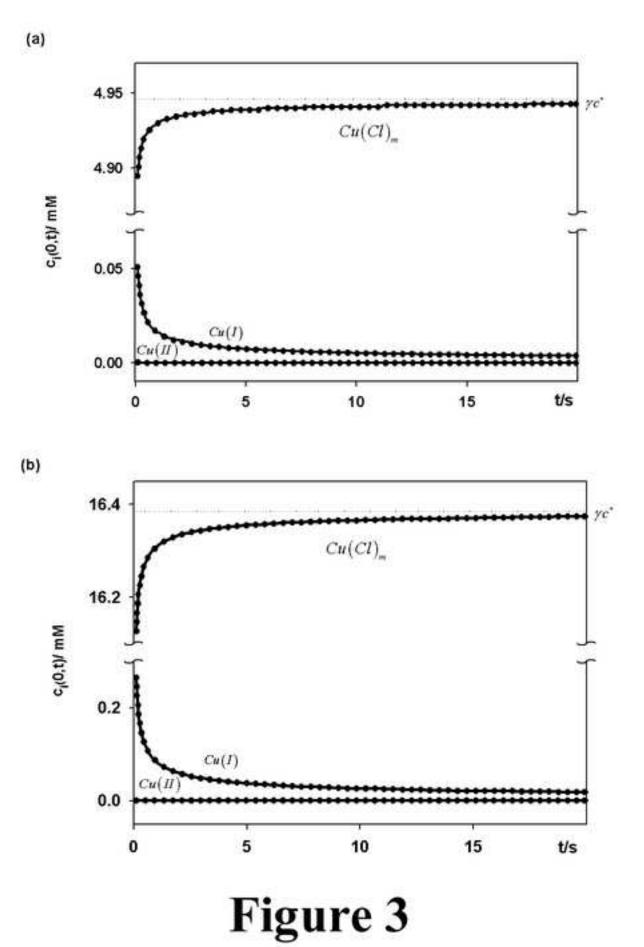
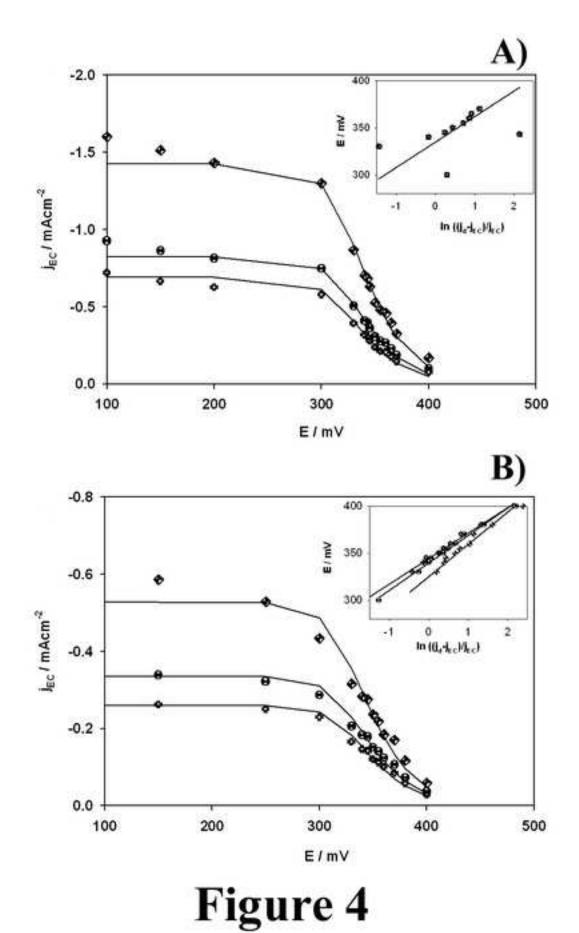


Figure 4 Click here to download high resolution image



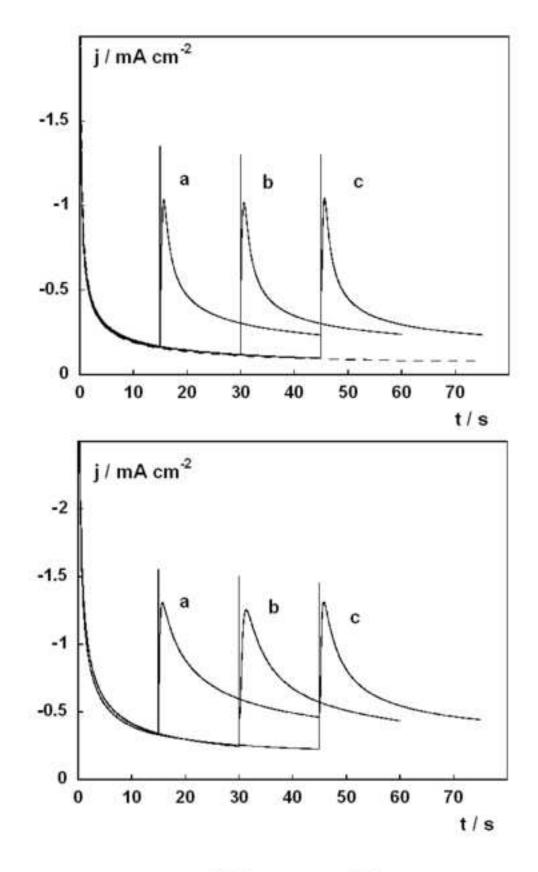


Figure 5

